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71M6541DT/71M6541FT/71M6541GT/ 71M6542FT/71M6542GT

Energy Meter ICs

General Description

The 71M6541DT/71M6541FT/71M6541GT/71M6542FT/71M6542GT (71M654xT) are 4th-generation single-phase metering systems-on-chips (SoCs) with a 5MHz, 8051-compatible MPU core, low-power RTC with digital temperature compensation, flash memory, and LCD driver. Our Single Converter Technology[®] with a 22-bit delta-sigma ADC, three or four analog inputs, digital temperature compensation, precision voltage reference, and a 32-bit computation engine (CE) support a wide range of metering applications with very few external components.

The 71M654xT devices support optional interfaces to the Maxim Integrated 71M6x01 series of isolated sensors offering BOM cost reduction, immunity to magnetic tamper, and enhanced reliability. Other features include an SPI interface, advanced power management, ultra-low-power operation in active and battery modes, 3KB/5KB shared RAM, and 32KB/64KB/128KB flash memory that can be programmed in the field with code and/or data during meter operation and the ability to drive up to six LCD segments per SEG driver pin. High processing and sampling rates combined with differential inputs offer a powerful platform for residential meters.

A complete array of code development tools, demonstration code, and reference designs enable rapid development and certification of meters that meet all ANSI and IEC electricity metering standards worldwide.

The 71M654xT family operates over the industrial temperature range and comes in 64-pin (71M6541DT/FT/GT) and 100-pin (71M6542FT/GT) lead(Pb)-free LQFP packages.

Applications

- Single-Phase Residential, Commercial, and Industrial Energy Meters

Ordering Information and Typical Operating Circuit appear at end of data sheet.

Single Converter Technology is a registered trademark of Maxim Integrated Products, Inc.

Benefits and Features

- SoC Integration and Unique Isolation Technique Reduces BOM Cost Without Sacrificing Performance
 - 0.1% Typical Accuracy Over 2000:1 Current Range
 - Exceeds IEC 62053/ANSI C12.20 Standards
 - Four-Quadrant Metering
 - 46-64Hz Line Frequency Range with the Same Calibration
 - Phase Compensation ($\pm 10^\circ$)
 - Independent 32-Bit Compute Engine
 - 32KB Flash, 3KB RAM (71M6541DT)
 - 64KB Flash, 5KB RAM (71M6541FT/71M6542FT)
 - 128KB Flash, 5KB RAM (71M6541GT/71M6542GT)
 - Built-In Flash Security
 - Up to Four Pulse Outputs with Pulse Count
 - 8-Bit MPU (80515), Up to 5 MIPS
 - Full-Speed MPU Clock in Brownout Mode
 - LCD Driver Allows Up to 6 Commons/Up to 56 Pins
 - Up to 51 Multifunction DIO Pins
 - Hardware Watchdog Timer (WDT)
 - Two UARTs for IR and AMR
 - IR LED Driver with Modulation
- Innovative Isolation Technology (Requires Companion 71M6xxx Sensor, also from Maxim Integrated) Eliminates Current Transformers
 - Two Current Sensor Inputs with Selectable Differential Mode
 - Selectable Gain of 1 or 8 for One Current Input to Support Shunts
 - High-Speed Wh/VARh Pulse Outputs with Programmable Width
- Digital Temperature Compensation Improves System Performance
 - Metrology Compensation
 - Accurate RTC for TOU Functions with Automatic Temperature Compensation for Crystal in All Power Modes
- Power Management Extends Battery Life During Power Outages
 - Three Battery-Backup Modes
 - Brownout Mode (BRN)
 - LCD Mode (LCD)
 - Sleep Mode (SLP)
- Wake-Up on Pin Events and Wake-On Timer
 - 1 μ A in Sleep Mode

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Absolute Maximum Ratings

(All voltages referenced to GNDA.)

Supplies and Ground Pins

V _{V3P3SYS} , V _{V3P3A}	-0.5V to +4.6V
V _{BAT} , V _{BAT_RTC}	-0.5V to +4.6V
GNDD.....	-0.1V to +0.1V

Analog Output Pins

V _{REF}	-10mA to +10mA, -0.5V to (V _{V3P3A} + 0.5V)
V _{DD}	-10mA to +10mA, -0.5V to +3.0V
V _{V3P3D}	-10mA to +10mA, -0.5V to +4.6V
V _{LCD}	-10mA to +10mA, -0.5V to +6.0V

Analog Input Pins

IAP, IAN, VA, IBP, IBN, VB*.....	-10mA to +10mA, -0.5V to (V _{V3P3A} + 0.5V)
XIN, XOUT.....	-10mA to +10mA, -0.5V to +3.0V

*71M6542FT/GT only.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

SEG and SEGDI0 Pins

Configured as SEG or COM Drivers. -1mA to +1mA, -0.5V to +6.0V
Configured as Digital Inputs-10mA to +10mA, -0.5V to +6.0V
Configured as Digital Outputs-10mA to +10mA, -0.5V to (V_{V3P3D} + 0.5V)

Digital Pins

Inputs (PB, RESET, RX, ICE_E, TEST).....-10mA to +10mA, -0.5V to +6.0V
Outputs (TX)..... -10mA to +10mA, -0.5V to (V_{V3P3D} + 0.5V)

Temperature

Operating Junction Temperature (peak, 100ms).....+140°C
Operating Junction Temperature (continuous).....+125°C
Storage Temperature.....-45°C to +140°C
Lead Temperature (soldering, 10s).....+300°C
Soldering Temperature (reflow).....+260°C

Electrical Characteristics

(Limits are production tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
RECOMMENDED OPERATING CONDITIONS					
V _{V3P3SYS} and V _{V3P3A} Supply Voltage	Precision metering operation	3.0		3.6	V
V _{BAT}	PLL_FAST = 1	2.65		3.8	V
	PLL_FAST = 0	2.40		3.8	
V _{BAT_RTC}		2.0		3.8	V
Operating Temperature		-40		+85	°C
INPUT LOGIC LEVELS					
Digital High-Level Input Voltage (V _{IH})		2			V
Digital Low-Level Input Voltage (V _{IL})				0.8	V
Input Pullup Current, (I _{IL}) E_RTXT, E_RST, E_TCLK		10		100	µA
Input Pullup Current, (I _{IL}) OPT_RX, OPT_TX		10		100	µA
Input Pullup Current, (I _{IL}) SPI_CSZ (SEGDI036)		10		100	µA
Input Pullup Current, (I _{IL}) Other Digital Inputs		-1		+1	µA
Input Pulldown Current (I _{IH}), ICE_E, RESET, TEST		10		100	µA
Input Pulldown Current, (I _{IH}) Other Digital Inputs		-1		+1	µA

Electrical Characteristics (continued)

(Limits are production tested at $T_A = +25^\circ\text{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
OUTPUT LOGIC LEVELS					
Digital High-Level Output Voltage (V_{OH})	$I_{LOAD} = 1\text{mA}$	$V_{V3P3D} - 0.4$			V
	$I_{LOAD} = 15\text{mA}$ (Note 1)	$V_{V3P3D} - 0.8$			V
Digital Low-Level Output Voltage (V_{OL})	$I_{LOAD} = 1\text{mA}$	0		0.4	V
	$I_{LOAD} = 15\text{mA}$ (Note 1)	0		0.8	V
BATTERY MONITOR					
Battery Voltage Equation: $3.3 + (BSENSE - BNOM3P3) \times 0.0252 + STEMP \times 2.79E-5 \text{ V}$					
Measurement Error	$V_{BAT} = 2.0\text{V}$	-3.5		+3.5	%
	$V_{BAT} = 2.5\text{V}$	-3.5		+3.5	
	$V_{BAT} = 3.0\text{V}$	-3.0		+3.0	
	$V_{BAT} = 3.8\text{V}$	-3.0		+3.0	
Input Impedance		260			k Ω
Passivation Current	$I_{BAT}(BCURR = 1) - I_{BAT}(BCURR = 0)$	50	100	165	μA
TEMPERATURE MONITOR					
Temperature Measurement Equation		$22.15 + STEMP \times 0.085 - 0.0023 \times STEMP \times [(STEMP_{T85P} - STEMP_{T22P}) / (T_{85P} - T_{22P}) - 12.857]$			$^\circ\text{C}$
Temperature Error (Note 1)	$T_A = +85^\circ\text{C}$	-3.2		+3.2	$^\circ\text{C}$
	$T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$	-2.65		+2.65	
	$T_A = -20^\circ\text{C}$	-3.4		+3.4	
	$T_A = -40^\circ\text{C}$	-3.8		+3.8	
V_{BAT_RTC} Charge per Measurement			2		μC
Duration of Temperature Measurement after TEMP_START			22	40	ms
SUPPLY CURRENT					
$V_{V3P3A} + V_{V3P3SYS}$ Supply Current (Note 1)	$V_{V3P3A} = V_{V3P3SYS} = 3.3\text{V}$; MPU_DIV = 3 (614kHz MPU clock); PLL_FAST = 1; PRE_E = 0		5.5	6.7	mA
	PLL_FAST = 0		2.6	3.5	
	PRE_E = 1		5.7	6.9	
	PLL_FAST = 0, PRE_E=1		2.6	3.6	

Electrical Characteristics (continued)

(Limits are production tested at $T_A = +25^\circ\text{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Dynamic Current			0.4	0.6	mA/MHz
V_{BAT} Current	Mission mode	-300		+300	nA
	Brownout mode		2.4	3.2	mA
	LCD mode (external V_{LCD})		0.4	108	nA
	LCD mode (internal V_{LCD} from DAC)		3.0	16	μA
	LCD mode (V_{BAT})		1.4	3.8	μA
	Sleep mode	-300		+300	nA
V_{BAT_RTC} Current	Brownout mode		400	650	nA
	LCD mode		1.8	4.1	μA
	Sleep mode, $T_A \leq 25^\circ\text{C}$		0.7	1.7	μA
	Sleep mode, $T_A = 85^\circ\text{C}$ (Note 1)		1.5	3.2	μA
Flash Write Current	Maximum flash write rate		7.1	9.3	mA
V_{V3P3D} SWITCH					
On-Resistance	$V_{V3P3SYS}$ to V_{V3P3D} , $I_{V3P3D} \leq 1\text{mA}$			11	Ω
	V_{BAT} to V_{V3P3D} , $I_{V3P3D} \leq 1\text{mA}$			11	
I_{OH}		9			mA
INTERNAL POWER FAULT COMPARATOR					
Response Time	100mV overdrive, falling	20		200	μs
	100mV overdrive, rising			200	
Falling Threshold, 3.0V Comparator		2.83	2.93	3.03	V
Falling Threshold, 2.8V Comparator		2.71	2.81	2.91	V
Difference between 3.0V and 2.8V comparators		47	136	220	mV
Falling Threshold, 2.25V Comparator		2.14	2.33	2.51	V
Falling Threshold, 2.0V Comparator		1.90	2.07	2.23	V
Difference between 2.25V and 2.0V Comparators		0.15	0.25	0.365	V

Electrical Characteristics (continued)

(Limits are production tested at $T_A = +25^\circ\text{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS	
Hysteresis	$T_A = +22^\circ\text{C}$	3.0V comparator	13	45	81	mV
		2.8V comparator	17	42	79	
		2.25V comparator	7	33	71	
		2.0V comparator	4	28	83	
2.5V REGULATOR						
V_{V2P5} Output Voltage	$V_{V3P3} = 3.0\text{V to } 3.8\text{V}$, $I_{\text{LOAD}} = 0\text{mA}$	2.55	2.65	2.75	V	
V_{V2P5} Load Regulation	$V_{\text{BAT}} = 3.3\text{V}$, $V_{V3P3} = 0\text{V}$, $I_{\text{LOAD}} = 0\text{mA to } 1\text{mA}$			40	mV	
Dropout Voltage	$I_{\text{LOAD}} = 5\text{mA}$			440	mV	
	$I_{\text{LOAD}} = 0\text{mA}$			200		
PSSR	$I_{\text{LOAD}} = 0\text{mA}$		5		mV/V	
CRYSTAL OSCILLATOR						
Maximum Output Power to Crystal				1	μW	
Adjustment Range, XOUT Capacitance	RTCA_ADJ = 0x7F to 0x00		15		pF	
PLL						
PLL Settling Time	Power-up		3		ms	
	PLL_FAST transition, low to high		3			
	PLL_FAST transition, high to low		3			
	Mode transition, sleep to mission		3			
LCD						
V_{LCD} Current	$V_{\text{LCD}} = 3.3\text{V}$, LCD_CLK = 0b11, all segments on		8.1		μA	
	$V_{\text{LCD}} = 3.3\text{V}$, LCD_CLK = 0b10, all segments on		4.6			
	$V_{\text{LCD}} = 3.3\text{V}$, all segments off			2.1		
	$V_{\text{LCD}} = 5.0\text{V}$, LCD_CLK = 0b11, all segments on		12.0			
	$V_{\text{LCD}} = 5.0\text{V}$, LCD_CLK = 0b10, all segments on		4.6			
	$V_{\text{LCD}} = 5.0\text{V}$, all segments off			3.0		
V_{REF}						
V_{REF} Output Voltage	$T_A = +22^\circ\text{C}$	1.193	1.195	1.197	V	
V_{REF} Output Impedance	$I_{\text{LOAD}} = -10\mu\text{A to } +10\mu\text{A}$			3.2	$\text{k}\Omega$	
V_{REF} Power Supply Sensitivity	$V_{V3P3A} = 3.0\text{V to } 3.6\text{V}$	-1.5		+1.5	mV/V	
V_{REF} Temperature Sensitivity (Note 1)		$V_{\text{REF}T} = V_{\text{REF}22} + (T-22)TC_1 + (T-22)^2TC_2$			V	
		$TC_1 = 151 - 2.77 \times \text{TRIMT}$			$\mu\text{V}/^\circ\text{C}$	
		$TC_2 = -0.528 - 0.00128 \times \text{TRIMT}$			$\mu\text{V}/^\circ\text{C}^2$	
V_{REF} Error (Note 1)		-40		+40	ppm/ $^\circ\text{C}$	

Electrical Characteristics (continued)

(Limits are production tested at $T_A = +25^\circ\text{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
ADC					
Recommended Input Range (All Analog Inputs Relative to V_{V3P3A})		-250		+250	mV Peak
Recommended Input Range, IADC0–IADC1, Preamp Enabled		-31.25		+31.25	mV Peak
Input Impedance	$f_{IN} = 65\text{Hz}$	40		100	k Ω
ADC Gain Error vs. Power Supply	$V_{IN} = 200\text{mV peak, } 65\text{Hz, } V_{V3P3A} = 3.0\text{V to } 3.6\text{V}$	-30		+70	ppm/%
Input Offset Voltage	Differential or single-ended modes	-10		+10	mV
THD	250mV peak, 65Hz, 64k points, Blackman-Harris window, FIR_LEN = 2, ADC_DIV = 1, PLL_FAST = 1, MUX_DIV = 2		-93		dB
	20mV peak, 65Hz, 64k points, Blackman-Harris window, FIR_LEN = 2, ADC_DIV = 1, PLL_FAST = 1, MUX_DIV = 2		-90		
LSB Size	FIR_LEN = 2, ADC_DIV = 1, PLL_FAST = 1, MUX_DIV = 2		151		nV
Digital Full Scale	FIR_LEN = 2, ADC_DIV = 1, PLL_FAST = 1, MUX_DIV = 2		$\pm 2,097,152$		LSB
PREAMPLIFIER					
Differential Gain		7.88	7.98	8.08	V/V
Gain Variation vs. Temperature	$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ (Note 1)	+15	-25	-30	ppm/ $^\circ\text{C}$
Gain Variation vs. V_{3P3}	$V_{V3P3} = 2.97\text{V to } 3.63\text{V}$ (Note 1)	-100		+100	ppm/%
Phase Shift	(Note 1)	+10		+22	m°
Preamp Input Current		3	6	9	μA
THD, Preamp + ADC	$V_{IN} = 30\text{mV}$		-88		dB
	$V_{IN} = 15\text{mV}$		-88		
Preamp Input Offset Voltage	IADC0 = IADC1 = $V_{V3P3} + 30\text{mV}$		-0.63		mV
	IADC0 = IADC1 = $V_{V3P3} + 15\text{mV}$		-0.57		
	IADC0 = IADC1 = V_{V3P3}		-0.56		
	IADC0 = IADC1 = $V_{V3P3} - 15\text{mV}$		-0.56		
	IADC0 = IADC1 = $V_{V3P3} - 30\text{mV}$		-0.55		
Phase Shift Over Temperature	(Note 1)	-0.03		+0.03	m°/C

Electrical Characteristics (continued)

(Limits are production tested at $T_A = +25^\circ\text{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
FLASH MEMORY					
Endurance		20,000			Cycles
Data Retention	$T_A = +25^\circ\text{C}$	100			Years
Byte Writes Between Erase Operations				2	Cycles
Write Time, per byte	Per 2 bytes if using SPI			50	μs
Page Erase Time				22	ms
Mass Erase Time				22	ms
SPI					
Data-to-Clock Setup Time		10			ns
Data Hold Time From Clock		10			ns
Output Delay, Clock to Data				40	ns
CS-to-Clock Setup Time		10			ns
Hold Time, CS to Clock		15			ns
Clock High Period		40			ns
Clock Low Period		40			ns
Clock Frequency (as a multiple of CPU frequency)				2.0	MHz/MHz
Space between SPI Transactions		4.5			CPU Cycles
EEPROM INTERFACE					
I ² C SCL Frequency	MPU clock = 4.9MHz, using interrupts		310		kHz
	MPU clock = 4.9MHz, bit-banging DIO2-DIO3		100		
3-Wire Write Clock Frequency	MPU clock = 4.9MHz, PLL_FAST = 0		160		kHz
	MPU clock = 4.9MHz, PLL_FAST = 1		490		
RESET					
Reset Pulse Width	(Note 1)	5			μs
Reset Pulse Fall Time	(Note 1)			1	μs
INTERNAL CALENDAR					
Year Date Range		2000		2255	Years

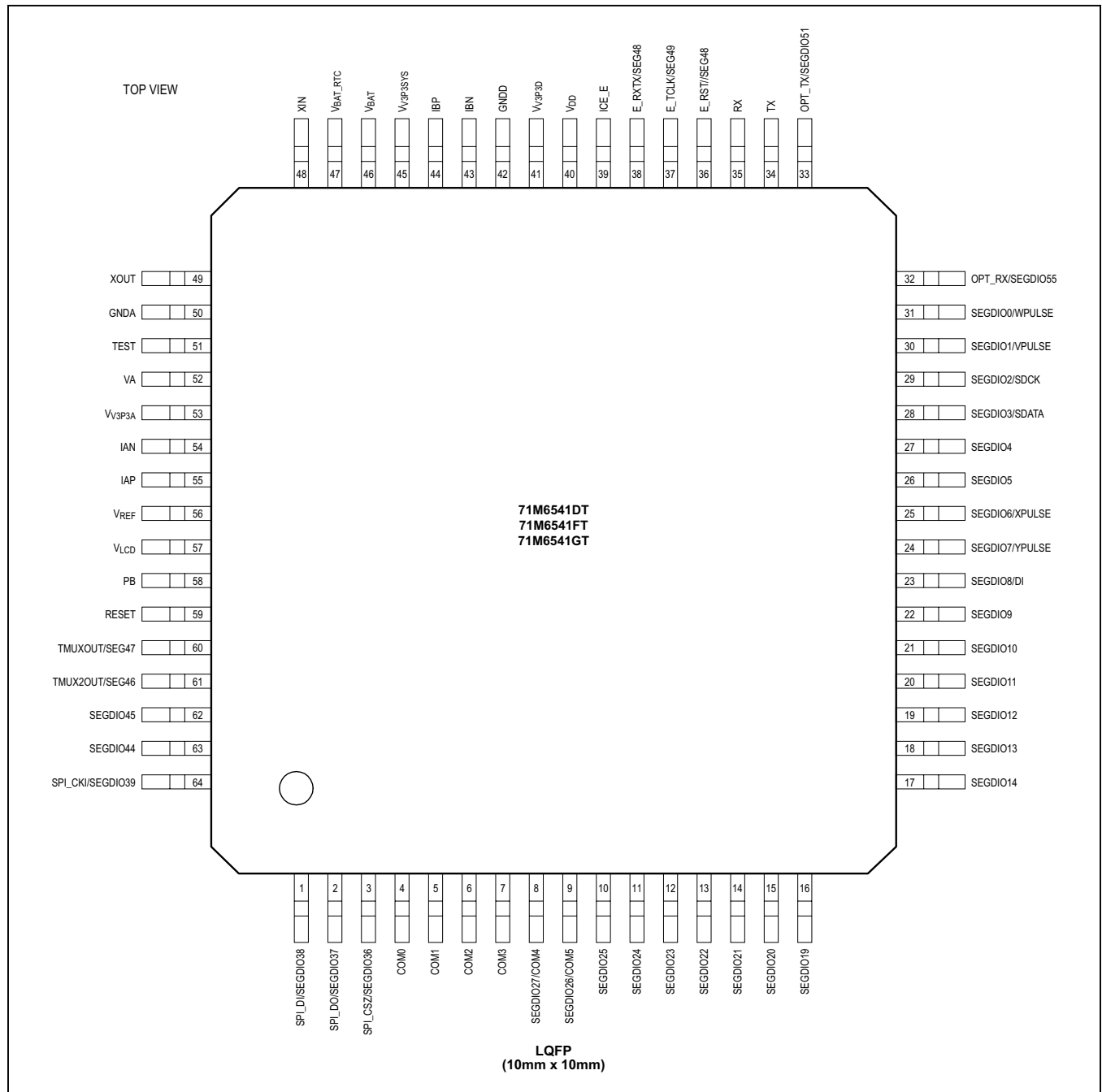
Recommended External Components

NAME	FROM	TO	FUNCTION	VALUE	UNITS
C1	V _{V3P3A}	GNDA	Bypass capacitor for 3.3V supply	≥ 0.1 ±20%	μF
C2	V _{V3P3D}	GNDD	Bypass capacitor for 3.3V output	0.1 ±20%	μF
CSYS	V _{V3P3SYS}	GNDD	Bypass capacitor for V _{V3P3SYS}	≥ 1.0 ±30%	μF
CVDD	V _{DD}	GNDD	Bypass capacitor for V _{DD}	0.1 ±20%	μF
CVLCD	V _{LCD}	GNDD	Bypass capacitor for V _{LCD} pin	≥ 0.1 ±20%	μF
XTAL	XIN	XOUT	32.768 kHz crystal; electrically similar to ECS .327-12.5-17X, Vishay XT26T or Suntsu SCP6–32.768kHz TR (load capacitance 12.5pF)	32.768	kHz
CXS (Note 2)	XIN	GNDA	Load capacitor values for crystal depend on crystal specifications and board parasitics. Nominal values are based on 3pF allowance for the sum of board and chip capacitance.	22 ±10%	pF
CXL (Note 2)	XOUT	GNDA		22 ±10%	pF

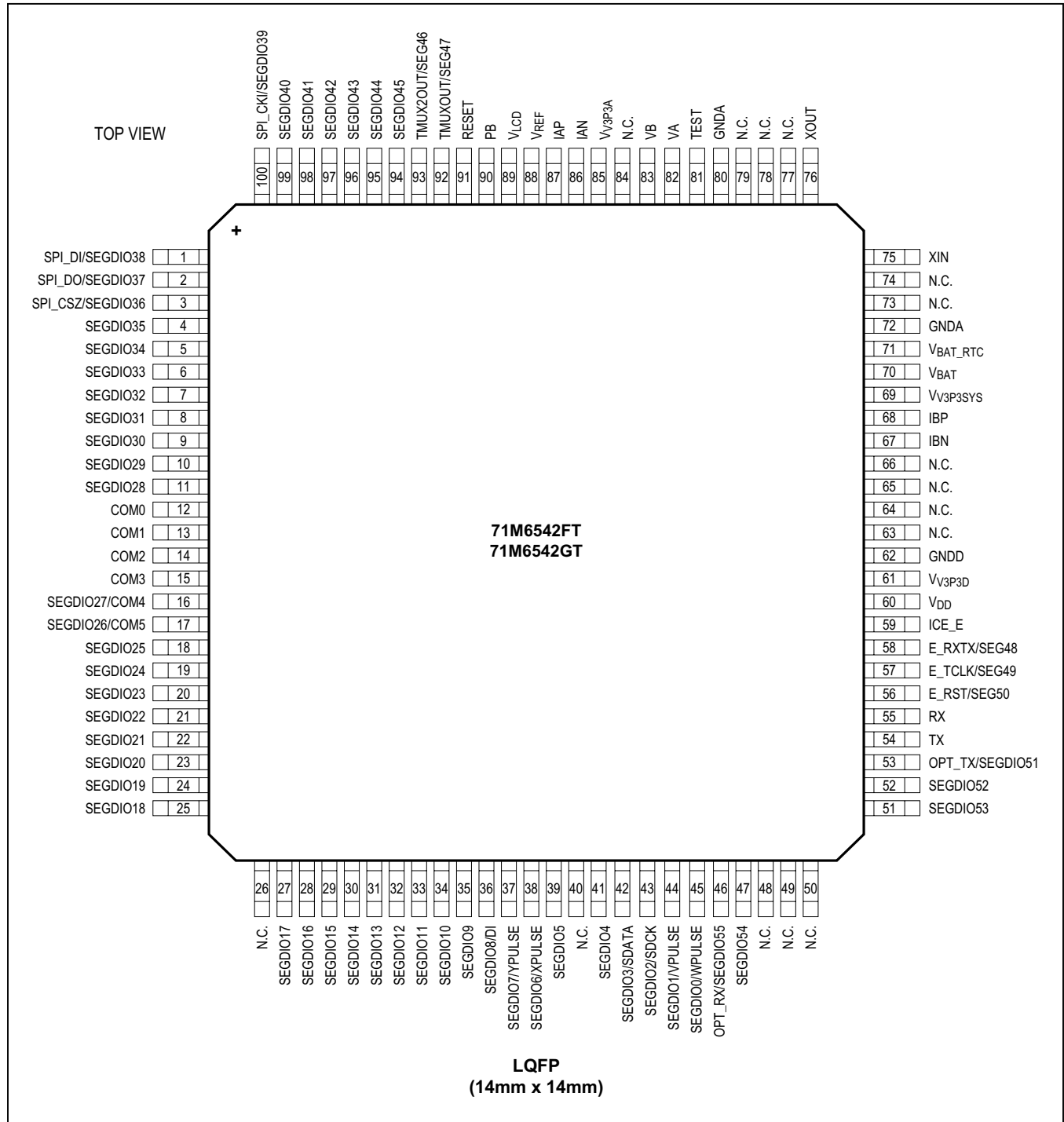
Note 1: Parameter not tested in production, guaranteed by design to six-sigma.

Note 2: If the capacitor values of CXS = 15pF and CXL = 10pF have already been installed, then changing the CXL value to 33pF and leaving CXS = 15pF would minimize rework.

Pin Configurations



Pin Configurations (continued)



Pin Descriptions

PIN		NAME	TYPE	CIRCUIT	FUNCTION
64	100				
POWER AND GROUND PINS					
50	72, 80	GNDA	P	—	Analog Ground. This pin should be connected directly to the ground plane.
42	62	GNDD	P	—	Digital Ground. This pin should be connected directly to the ground plane.
53	85	V _{V3P3A}	P	—	Analog Power Supply. A 3.3V power supply should be connected to this pin. V _{V3P3A} must be the same voltage as V _{V3P3SYS} .
45	69	V _{V3P3SYS}	P	—	System 3.3V supply. This pin should be connected to a 3.3V power supply.
41	61	V _{V3P3D}	O	13	Auxiliary Voltage Output of the Chip. In mission mode, this pin is connected to V _{V3P3SYS} by the internal selection switch. In BRN mode, it is internally connected to V _{BAT} . V _{V3P3D} is floating in LCD and sleep mode. A 0.1μF bypass capacitor to ground must be connected to this pin.
40	60	V _{DD}	O	—	Output of the 2.5V Regulator. This pin is powered in MSN and BRN modes. A 0.1μF bypass capacitor to ground should be connected to this pin.
57	89	V _{LCD}	O	—	Output of the LCD DAC. A 0.1μF bypass capacitor to ground should be connected to this pin.
46	70	V _{BAT}	P	12	Battery Backup Pin to Support the Battery Modes (BRN, LCD). A battery or super capacitor is to be connected between V _{BAT} and GNDD. If no battery is used, connect V _{BAT} to V _{V3P3SYS} .
47	71	V _{BAT_RTC}	P	12	RTC and Oscillator Power Supply. A battery or super capacitor is to be connected between V _{BAT} and GNDD. If no battery is used, connect V _{BAT_RTC} to V _{V3P3SYS} .
ANALOG PINS					
55, 54	87, 86	IAP-IAN	I	6	Differential or Single-Ended Line Current Sense Inputs. These pins are voltage inputs to the internal A/D converter. Typically, they are connected to the outputs of current sensors. Unused pins must be tied to V _{V3P3A} . Pins IBP-IBN may be configured for communication with the remote sensor interface (71M6x01).
44, 43	68, 67	IBP-IBN			
52	82, 83	VA, VB†	I	6	Line Voltage Sense Inputs. These pins are voltage inputs to the internal A/D converter. Typically, they are connected to the outputs of resistor-dividers. Unused pins must be tied to V _{V3P3A} .
56	88	V _{REF}	O	9	Voltage Reference for the ADC. This pin should be left unconnected (floating).
48	75	XIN	I	8	Crystal Inputs. A 32.768kHz crystal should be connected across these pins. Typically, a 22pF capacitor is also connected from XIN to GNDA and a 22pF capacitor is connected from XOUT to GNDA. It is important to minimize the capacitance between these pins. See the crystal manufacturer data sheet for details. If an external clock is used, a 150mV _{P-P} clock signal should be applied to XIN, and XOUT should be left unconnected.
49	76	XOUT			

Pin Descriptions (continued)

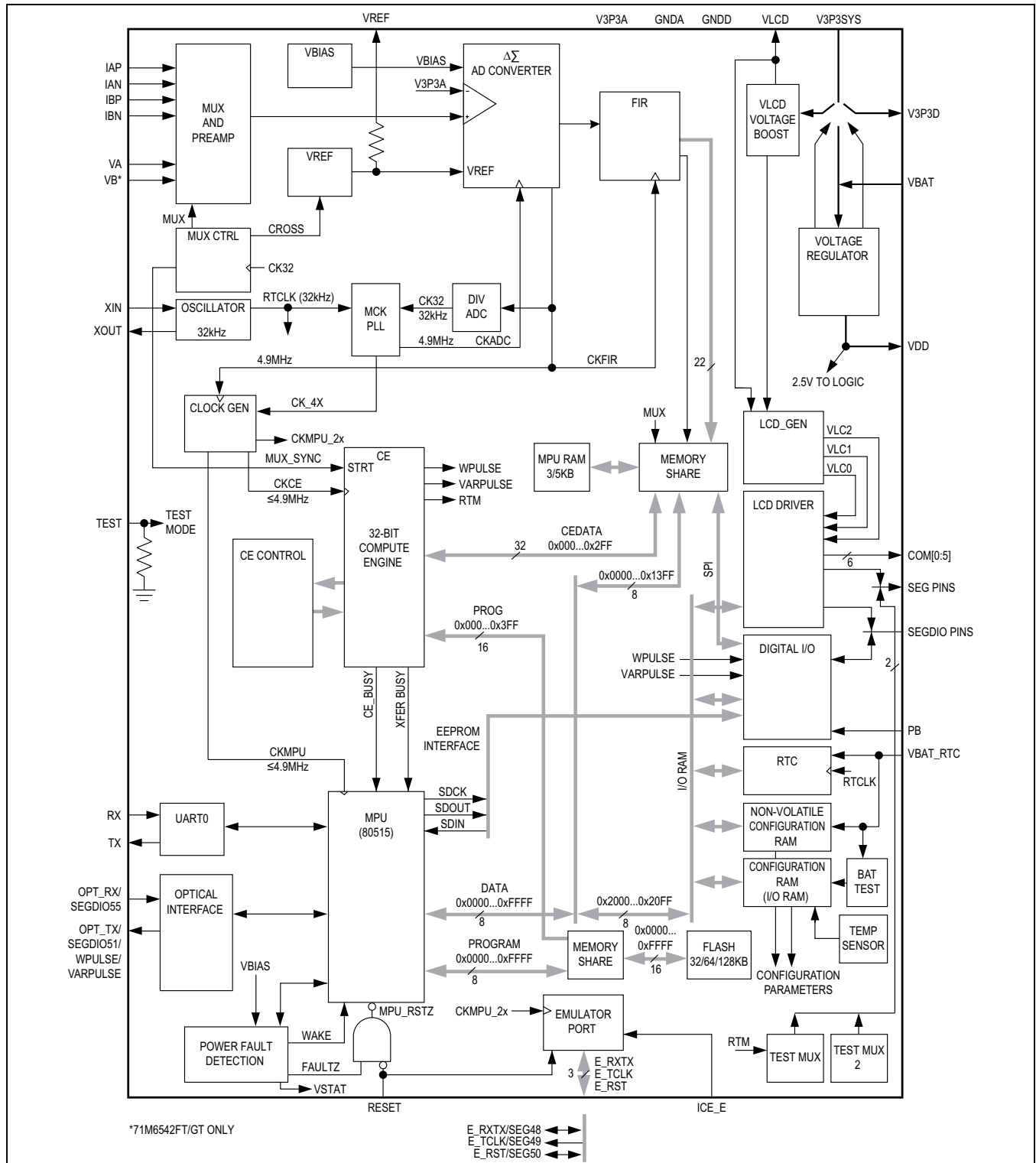
PIN		NAME	TYPE	CIRCUIT	FUNCTION
64	100				
DIGITAL PINS					
4-7	12-15	COM0-COM3	O	5	LCD Common Outputs. These four pins provide the select signals for the LCD display.
31	45	SEGDI00/WPULSE	I/O	3, 4, 5	Multiple-Use Pins. Configurable as either LCD segment driver or DIO. Alternative functions with proper selection of associated I/O RAM registers are: SEGDI00 = WPULSE SEGDI01 = VPULSE SEGDI02 = SDCK SEGDI03 = SDATA SEGDI06 = XPULSE SEGDI07 = YPULSE SEGDI08 = DI SEGDI16 = RX3 SEGDI17 = TX3 Unused pins must be configured as outputs or terminated to V3P3/GNDD.
30	44	SEGDI01/VPULSE			
29	43	SEGDI02/SDCK			
28	42	SEGDI03/SDATA			
27	41	SEGDI04			
26	39	SEGDI05			
25	38	SEGDI06/XPULSE			
24	37	SEGDI07/YPULSE			
23	36	SEGDI08/DI			
22-17	35-30	SEGDI0[9:14]			
—	29-27	SEGDI0[15:17]			
—	25	SEGDI0[18]			
16-10	24-18	SEGDI0[19:25]			
—	11-4	SEGDI0[28:35]			
63-62	95-94	SEGDI0[44:45]			
—	99-96	SEGDI0[40:43]			
—	52	SEGDI052			
—	51	SEGDI053			
—	47	SEGDI054			
9	17	SEGDI026/COM5	I/O	3, 4, 5	Multiple-Use Pins. Configurable as either LCD segment driver or DIO with alternative function (LCD common drivers).
8	16	SEGDI027/COM4			
3	3	SPI_CSZ/SEGDI036	I/O	3, 4, 5	Multiple-Use Pins. Configurable as either LCD segment driver or DIO with alternative function (SPI interface).
2	2	SPI_DO/SEGDI037			
1	1	SPI_DI/SEGDI038			
64	100	SPI_CK/SEGDI039			
33	53	OPT_TX/SEGDI051	I/O	3, 4, 5	Multiple-Use Pins, configurable as either LCD segment driver or DIO with alternative function (optical port/UART1)
32	46	OPT_RX/SEGDI055			
38	58	E_RXTX/SEG48	I/O	1, 4, 5	Multiuse Pins. Configurable as either emulator port pins (when ICE_E pulled high) or LCD segment drivers (when ICE_E tied to GND).
36	56	E_RST/SEG50			
37	57	E_TCLK/SEG49			
39	59	ICE_E	I	2	ICE Enable. When zero, E_RST, E_TCLK, and E_RXTX become SEG50, SEG49, and SEG48, respectively. For production units, this pin should be pulled to GND to disable the emulator port.
60	92	TMUXOUT/SEG47	O	4, 5	Multiple-Use Pins. Configurable as either multiplexer/clock output or LCD segment driver using the I/O RAM registers.
61	93	TMUX2OUT/SEG46			
59	91	RESET	I	2	Chip Reset. This input pin is used to reset the chip into a known state. For normal operation, this pin is pulled low. To reset the chip, this pin should be pulled high. This pin has an internal 30FA (nominal) current source pulldown. No external reset circuitry is necessary.

Pin Descriptions (continued)

PIN		NAME	TYPE	CIRCUIT	FUNCTION
64	100				
35	55	RX	I	3	UART0 Input. If this pin is unused it must be terminated to V _{V3P3D} or GNDD.
34	54	TX	O	4	UART0 Output
51	81	TEST	I	7	Enables Production Test. This pin must be grounded in normal operation.
58	90	PB	I	3	Pushbutton Input. This pin must be at GNDD when not active or unused. A rising edge sets the WF_PB flag. It also causes the part to wake up if it is in SLP or LCD mode. PB does not have an internal pullup or pulldown resistor.
—	26, 40, 48, 49, 50, 63, 64, 65, 66, 73, 74, 77, 78, 79, 84	N.C.	N.C.	—	No Connection. Do not connect these pins.

I = Input, O = Output, P = Power

Block Diagram



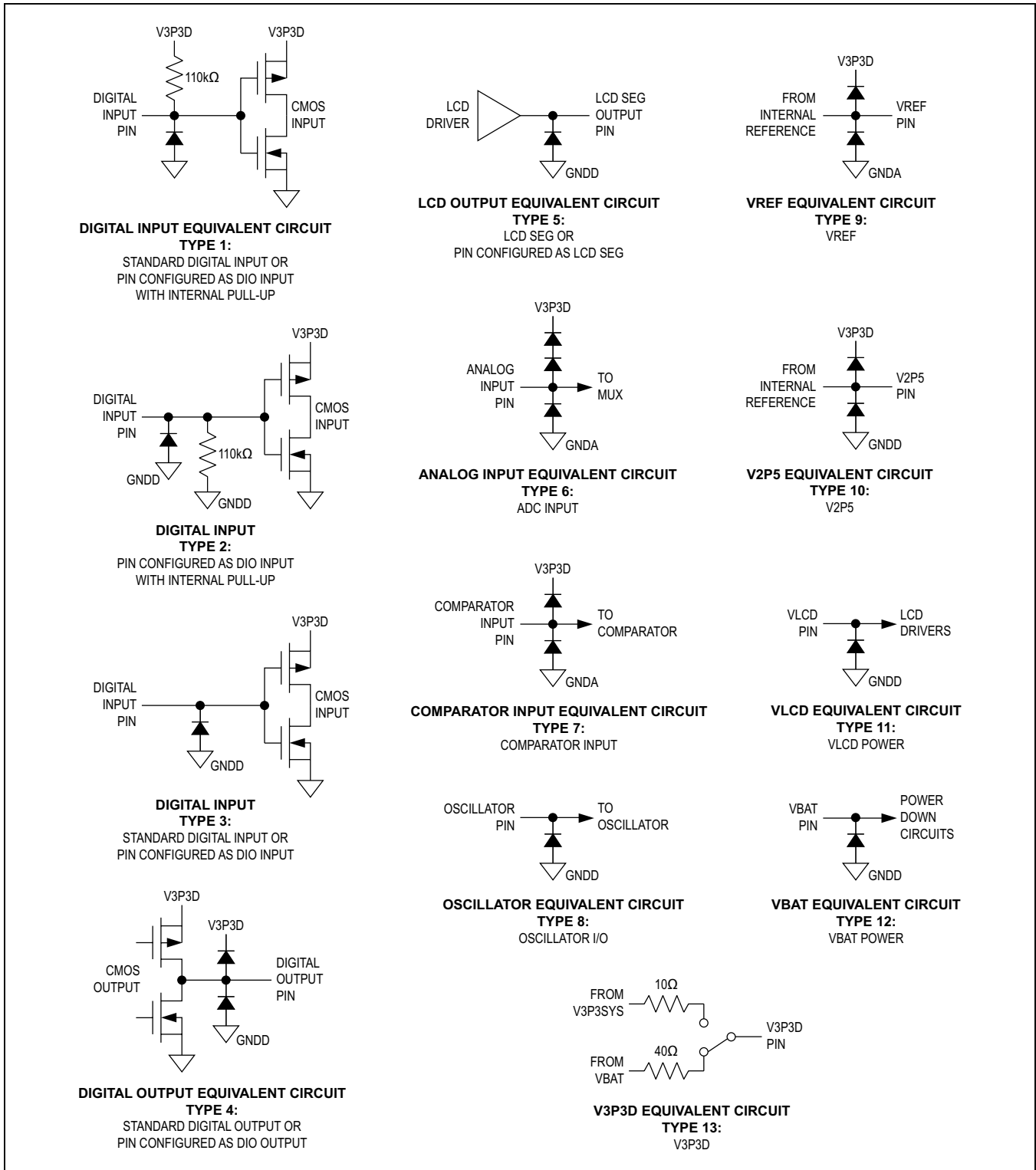


Figure 1. I/O Equivalent Circuits

Hardware Description

The 71M6541DT/FT/GT and 71M6542FT/GT single-chip energy meter ICs integrate all primary functional blocks required to implement a solid-state residential electricity meter. Included on the chip are the following:

- An analog front-end (AFE) featuring a 22-bit second-order sigma-delta ADC
- An independent 32-bit digital computation engine (CE) to implement DSP functions
- An 8051-compatible microprocessor (MPU) which executes one instruction per clock cycle (80515)
- A precision voltage reference (V_{REF})
- A temperature sensor for digital temperature compensation:
 - Metrology digital temperature compensation (MPU)
 - Automatic RTC digital temperature compensation operational in all power states
- LCD drivers
- RAM and flash memory
- A real-time clock (RTC)
- A variety of I/O pins
- A power-failure interrupt
- A zero-crossing interrupt
- Selectable current sensor interfaces for locally-connected sensors as well as isolated sensors (i.e., using the 71M6x01 companion IC with a shunt resistor sensor)
- Resistive shunt and current transformers are supported

Resistive shunts and current transformer (CT) current sensors are supported. Resistive shunt current sensors may be connected directly to the 71M654xT device or isolated using a companion 71M6x01 isolator IC in order to implement a variety of single-phase/split-phase (71M6541DT/FT/GT) or two-phase (71M6542FT/GT) metering configurations. An inexpensive, small pulse transformer is used to isolate the 71M6x01 isolated sensor from the 71M654xT. The 71M654xT performs digital communications bidirectionally with the 71M6x01 and also provides power to the 71M6x01 through the isolating pulse transformer. Isolated (remote) shunt current sensors are connected to the differential input of the 71M6x01. Included on the 71M6x01 companion isolator chip are:

- Digital isolation communications interface
- An analog front-end (AFE)

- A precision voltage reference (V_{REF})
- A temperature sensor (for digital temperature compensation)
- A fully differential shunt resistor sensor input
- A preamplifier to optimize shunt current sensor performance
- Isolated power circuitry obtains dc power from pulses sent by the 71M654xT

In a typical application, the 32-bit compute engine (CE) of the 71M654xT sequentially processes the samples from the voltage inputs on analog input pins and from the external 71M6x01 isolated sensors and performs calculations to measure active energy (Wh) and reactive energy (VARh), as well as A²h, and V²h for four-quadrant metering. These measurements are then accessed by the MPU, processed further and output using the peripheral devices available to the MPU.

In addition to advanced measurement functions, the clock function allows the 71M6541DT/FT/GT and 71M6542FT/GT to record time-of-use (TOU) metering information for multi-rate applications and to time-stamp tamper or other events. Measurements can be displayed on 3.3V LCDs commonly used in low-temperature environments. Flexible mapping of LCD display segments facilitate integration of existing custom LCDs. Design trade-off between the number of LCD segments and DIO pins can be implemented in software to accommodate various requirements.

In addition to the temperature-trimmed ultra-precision voltage reference, the on-chip digital temperature compensation mechanism includes a temperature sensor and associated controls for correction of unwanted temperature effects on measurement and RTC accuracy, e.g., to meet the requirements of ANSI and IEC standards. Temperature-dependent external components such as crystal oscillator, resistive shunts, current transformers (CTs) and their corresponding signal conditioning circuits can be characterized and their correction factors can be programmed to produce electricity meters with exceptional accuracy over the industrial temperature range.

One of the two internal UARTs is adapted to support an Infrared LED with internal drive and sense configuration and can also function as a standard UART. The optical output can be modulated at 38kHz. This flexibility makes it possible to implement AMR meters with an IR interface. See the [Block Diagram](#).

Analog Front-End (AFE)

The AFE functions as a data acquisition system, controlled by the MPU. When used with locally connected sensors, as shown in Figure 2, the analog input signals (IAP-IAN, VA and IBP-IBN) are multiplexed to the ADC input and sampled by the ADC.

The ADC output is decimated by the FIR filter and stored in CE RAM where it can be accessed and processed by the CE.

When a remote isolated shunt sensor is connected via the 71M6x01, the samples associated with this current channel are not routed to the multiplexer, and are instead

transferred digitally to the 71M6541DT/FT/GT through the digital isolation interface and are directly stored in CE RAM.

When local sensors are used, the analog input signals (IAP-IAN, VA, IBP-IBN and VB) are multiplexed to the ADC input and sampled by the ADC. The ADC output is decimated by the FIR filter and stored in CE RAM where it can be accessed and processed by the CE.

When a remote isolated shunt sensor is connected using a 71M6x01 connected to the 71M6542FT/GT, the samples associated with this current channel are not routed to the multiplexer, and are instead transferred digitally to the 71M6542FT/GT through the digital isolation interface and are directly stored in CE RAM.

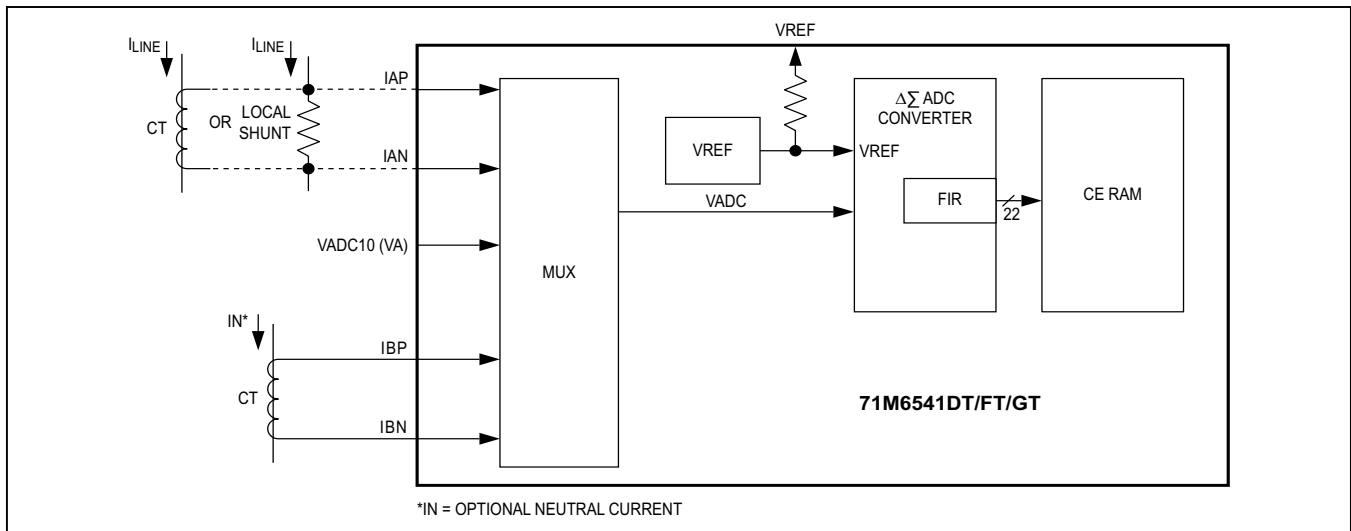


Figure 2. 71M6541DT/FT/GT Operating with Local Sensors

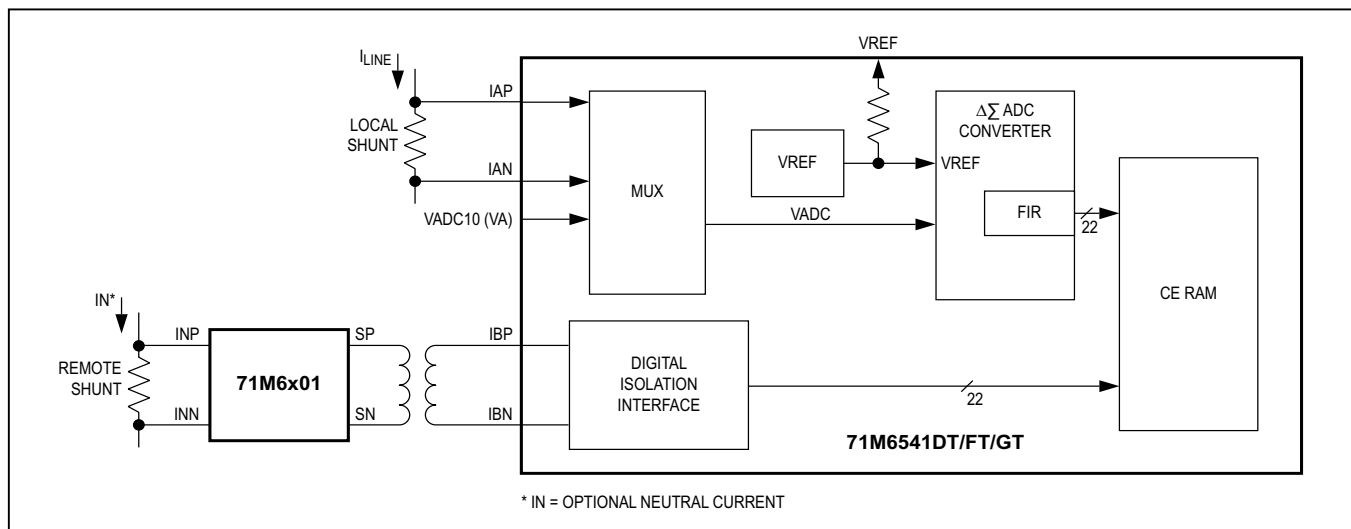


Figure 3. 71M6541DT/FT/GT Operating with Remote Sensor for Neutral Current

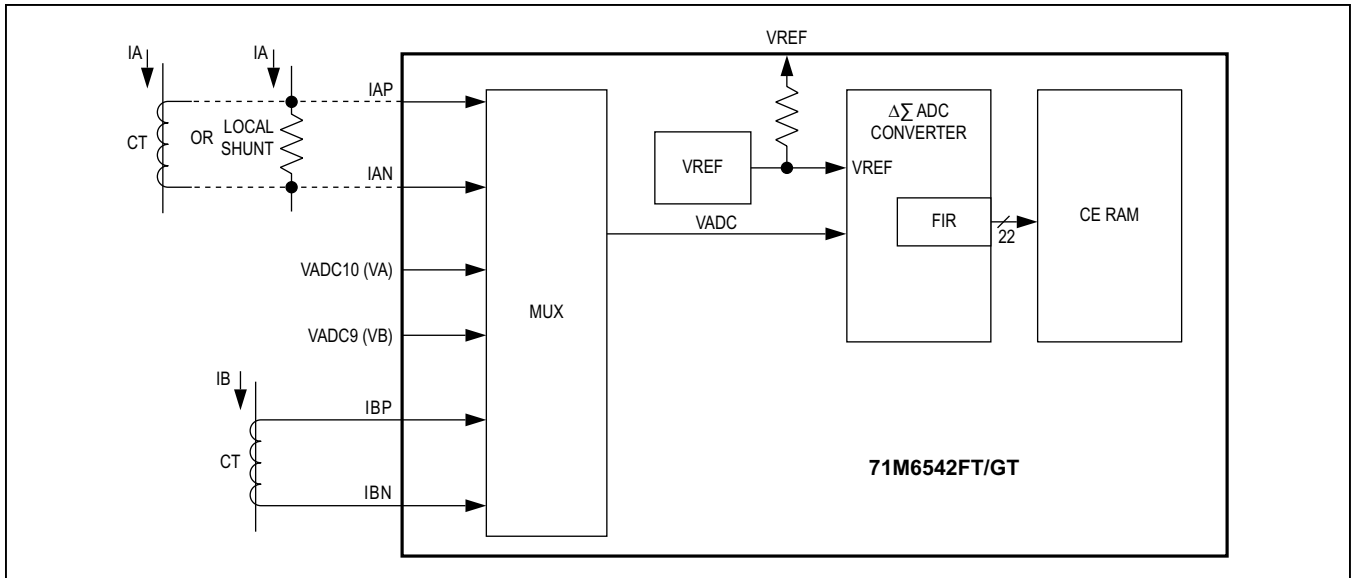


Figure 4. 71M6542FT/GT Operating with Local Sensors

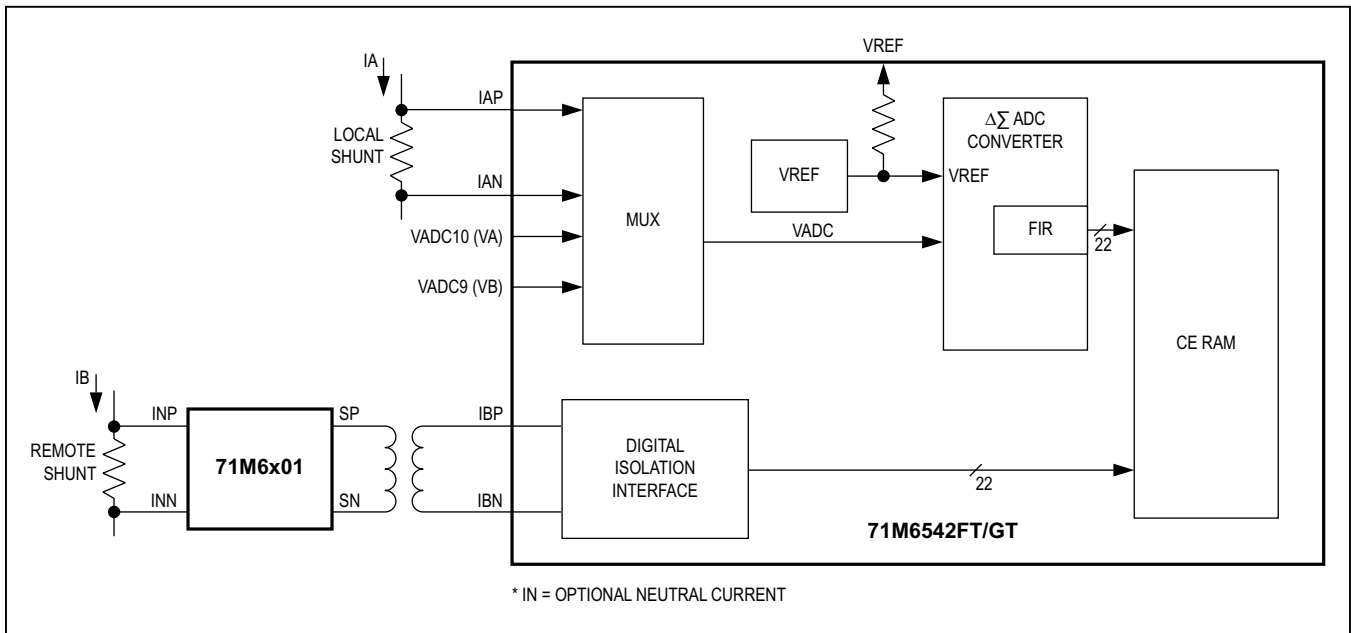


Figure 5. 71M6542FT/GT Operating with Remote Sensor for Neutral Current

Signal Input Pins

The 71M6541DT/FT/GT features five ADC inputs. The 71M6542FT/GT features six ADC inputs.

IAP-IAN and IBP-IBN are intended for use as current sensor inputs. These four current sensor inputs can be configured as two single-ended inputs, or (more frequently) can be paired to form two differential inputs. For best performance, it is recommended to configure the current sensor inputs as differential inputs (i.e., IAP-IAN and IBP-IBN). The first differential input (IAP-IAN) features a pre-amplifier with a selectable gain of 1 or 8, and is intended for direct connection to a shunt resistor sensor, and can also be used with a current transformer (CT). The remaining differential pair (i.e., IBP-IBN) may be used with CTs, or may be enabled to interface to a remote 71M6x01 isolated current sensor providing isolation for a shunt resistor sensor using a low cost pulse transformer.

The remaining input in the 71M6541DT/FT/GT (VA) is single-ended, and is senses line voltage in single-phase meter applications. The 71M6542FT/GT features an additional single-ended voltage sensing input (VB) to support biphasic applications. These single-ended inputs are referenced to the V_{V3P3A} pin.

All analog signal input pins measure voltage. In the case of shunt current sensors, currents are sensed as a voltage drop in the shunt resistor sensor. Referring to [Figure 2](#), shunt sensors can be connected directly to the 71M654xT (referred to as a 'local' shunt sensor) or connected through an isolated 71M6x01 (referred to as a 'remote' shunt sensor) ([Figure 3](#)). In the case of current transformers, the current is measured as a voltage across a burden resistor that is connected to the secondary winding of the CT. Meanwhile, line voltages are sensed through resistive voltage dividers. The VA and VB pins (VB is available in the 71M6542FT/GT only) are single-ended and their common return is the V_{V3P3A} pin.

Pins IAP-IAN can be programmed individually to be differential or single-ended. For most applications IAP-IAN are configured as a differential input to work with a shunt or CT directly interfaced to the IAP-IAN differential input with the appropriate external signal conditioning components.

The performance of the IAP-IAN pins can be enhanced by enabling a preamplifier with a fixed gain of 8. When the PRE_E bit = 1, IAP-IAN become the inputs to the 8x pre-amplifier, and the output of this amplifier is supplied to the multiplexer. The 8x amplification is useful when current sensors with low sensitivity, such as shunt resistors, are used. With PRE_E set, the IAP-IAN input signal amplitude is restricted to 31.25 mV peak.

For the 71M654xT application utilizing two shunt resistor sensors the IAP-IAN pins are configured for differential mode to interface to a local shunt by setting the DIFFA_E control bit. Meanwhile, the IBP-IBN pins are re-configured as digital balanced pair to communicate with a 71M6x01 isolated sensor interface by setting the RMT_E control bit. The 71M6x01 communicates with the 71M654xT using a bidirectional digital data stream through an isolating low-cost pulse transformer. The 71M654xT also supplies power to the 71M6x01 through the isolating transformer.

When using current transformers the IBP-IBN pins are configured as local analog inputs (RMT_E = 0). The IAP-IAN pins cannot be configured as a remote sensor interface.

Input Multiplexer

When operating with local sensors, the input multiplexer sequentially applies the input signals from the analog input pins to the input of the ADC. One complete sampling sequence is called a multiplexer frame. The multiplexer of the 71M6541DT/FT/GT can select up to three input signals (IAP-IAN, VA, and IBP-IBN) per multiplexer frame. The multiplexer of the 71M6542FT/GT adds the VB signal for a total of four inputs. The multiplexer always starts at state 1 and proceeds until as many states as determined by MUX_DIV[3:0] have been converted.

The 71M6541DT/FT/GT and 71M6542FT/GT each require a unique CE code that is written for the specific application. Moreover, each CE code requires specific AFE and MUX settings in order to function properly. Contact Maxim Integrated for specific information about alternative CE codes.

For a basic single-phase application, the IAP-IAN current input is configured for differential mode and the VA pin is single-ended and is typically connected to the phase voltage via a resistor divider. The IBP-IBN differential input may be optionally used to sense the neutral current. This configuration implies that the multiplexer applies a total of three inputs to the ADC. In this configuration IAP-IAN (line current), IBP-IBN (neutral current) and VA (line voltage) are sampled. If the application doesn't require sampling the neutral current, the IBP-IBN inputs can be connected to V_{V3P3A} and the current sensor for the neutral current measurement can be omitted.

If a tamper sensor in the neutral path is required, there are two options: first, the two current inputs (the pin pairs IAP-IAN and IBP-IBN) can be configured for differential mode. In this configuration, the multiplexer sequentially applies each of the three inputs to the ADC. Alternately, the IAP-IAN pin pair can be configured as a differential input and connected to a local current shunt, and IBP-IBN

configured to connect to an isolated 71M6x01 isolated sensor. When the remote isolated sensor is used, time slot 2 is unused and ignored by the CE, as the samples corresponding to the remote sensor (IBP-IBN) do not pass through the multiplexer and are stored directly in CE RAM. The remote current sensor channel is sampled during the second half of the multiplexer frame and its timing relationship to the VA voltage is precisely known so that delay compensation can be properly applied.

The 71M6542FT/GT adds the ability to sample a second phase voltage (applied at the VB pin), which makes it suitable for meters with two voltage and two current sensors, such as meters implementing Equation 2 for dual-phase operation ($P = VA \times IA + VB \times IB$).

For both multiplexer sequences (three-input or four-input), the frame duration is 13 CK32 cycles (where CK32 = 32,768Hz) making the resulting sample rate $32,768\text{Hz}/13 = 2520.6\text{Hz}$.

Delay Compensation

When measuring the energy of a phase (i.e., Wh and VARh) in a service, the voltage and current for that phase must be sampled at the same instant. Otherwise, the phase difference, Φ , introduces errors.

$$\phi = \frac{t_{\text{delay}}}{T} \cdot 360^\circ = t_{\text{delay}} \cdot f \cdot 360^\circ$$

Where f is the frequency of the input signal, $T = 1/f$ and t_{delay} is the sampling delay between current and voltage.

Traditionally, sampling is accomplished by using two A/D converters per phase (one for voltage and the other one for current) controlled to sample simultaneously. Our Single Converter Technology, however, exploits the 32-bit signal processing capability of its CE to implement “constant delay” allpass filters. The allpass filter corrects for the conversion time difference between the voltage and

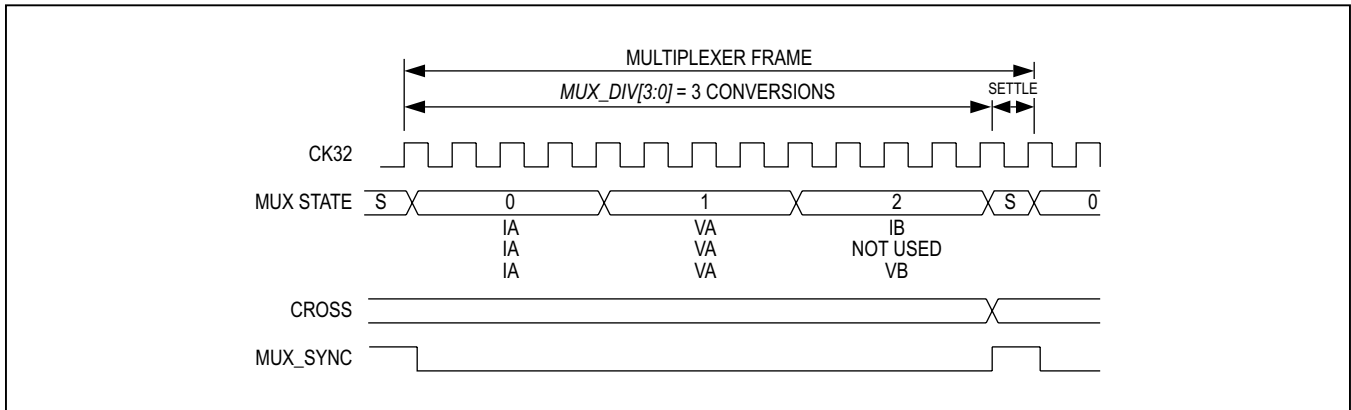


Figure 6. Multiplexer Sequence with $MUX_DIV = 3$

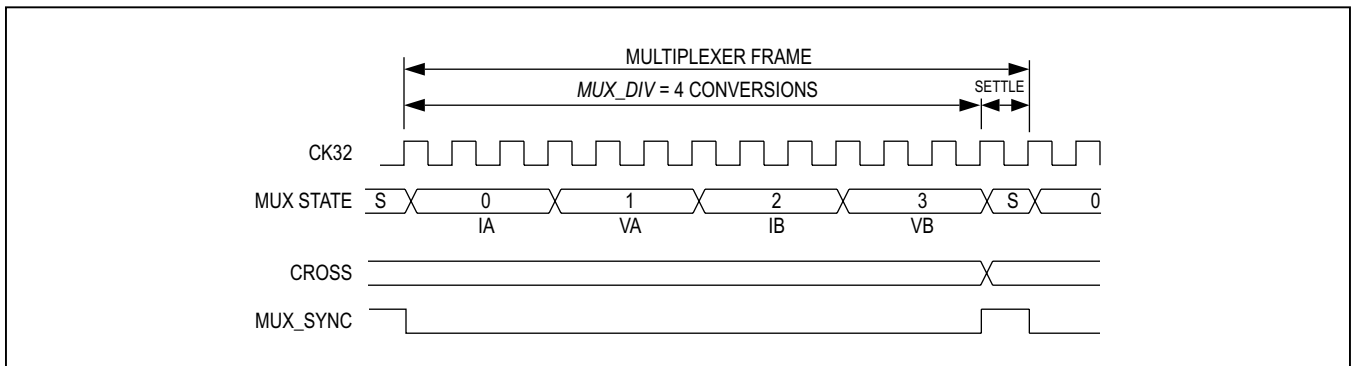


Figure 7. Multiplexer Sequence with $MUX_DIV = 4$